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FDS6675BZ P-Channel PowerTrench[®] MOSFET -30V, -11A, 13mΩ

General Description

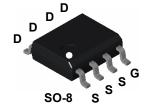
This P-Channel MOSFET is producted using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance.

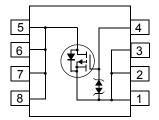
This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)}$ = 13m Ω at V_{GS} = -10V, I_D = -11A
- Max r_{DS(on)} = 21.8mΩ at V_{GS} = -4.5V, I_D = -9A
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 5.4 KV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handing capability
- RoHS Compliant





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		-30	V
V _{GS}	Gate to Source Voltage		±25	V
	Drain Current -Continuous	(Note 1a)	-11	^
D	-Pulsed		-55	— A
	Power Dissipation for Single Operation	(Note 1a)	2.5	
P _D		(Note 1b)	1.2	W
		(Note 1c)	1.0	
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note 1a)	50	°C/W
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case (Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS6675BZ	FDS6675BZ	13"	12mm	2500 units

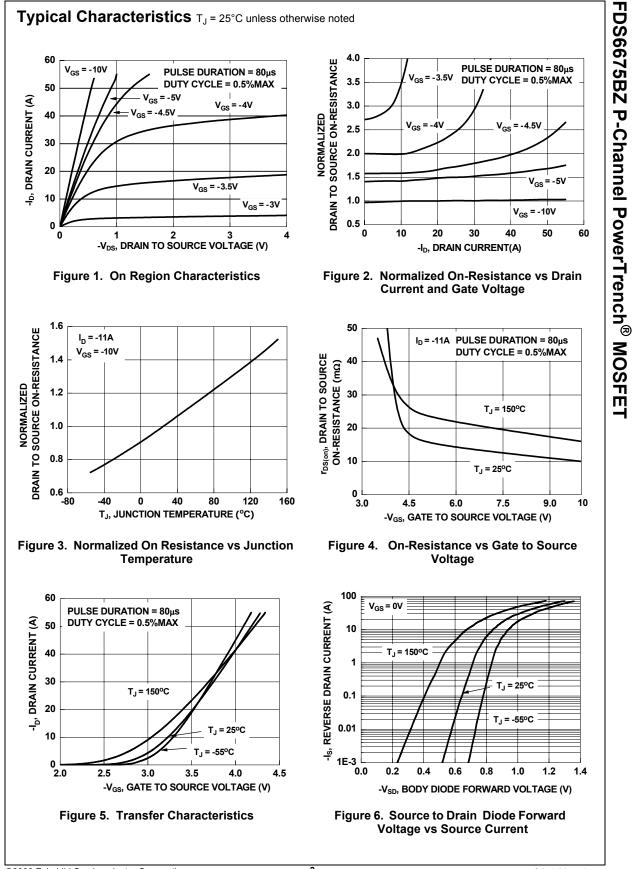
March 2009

eristics rain to Source Breakdown Voltage reakdown Voltage Temperature pefficient roo Gate Voltage Drain Current rate to Source Leakage Current ristics (Note 2) restrict Source Threshold Voltage remperature Coefficient rain to Source On Resistance	$\begin{split} & _{D} = -250 \mu A, V_{GS} = 0V \\ & _{D} = -250 \mu A, \text{ referenced to} \\ &25^{\circ}\text{C} \\ &V_{DS} = -24V, V_{GS} = 0V \\ &V_{GS} = \pm 25V, V_{DS} = 0V \\ \hline &V_{GS} = \pm 25V, V_{DS} = 0V \\ \hline &V_{GS} = -250 \mu A, \text{ referenced to} \\ & _{D} = -250 \mu A, \text{ referenced to} \\ &25^{\circ}\text{C} \\ \hline &V_{GS} = -10V, _{D} = -11A \\ \hline &V_{GS} = -10V, _{D} = -11A \\ \hline &V_{SS} = -10V, _{SS} = -10V, _{SS} = -10V, _{SS} = -10V \\ \hline &V_{SS} = -10V, _{SS} = -10V, _{SS} = -10V \\ \hline &V_{SS} = -10V \\ $	-30	-20 -2 15.7	-1 ±10	V mV/°C μΑ μΑ V
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emperature Coefficient	25°C V _{GS} = -10V , I _D = -11A		15.7		
	V _{GS} = -10V , I _D = -11A		10.7		mV/°C
ain to Source On Resistance					IIIV/ C
ain to Source On Resistance			10.8	13.0	-
	V _{GS} = -4.5V, I _D = -9A		17.4	21.8	mΩ
	V _{GS} = -10V, I _D = -11A T _J = 125°C		15.0	18.8	
orward Transconductance	$V_{DS} = -5V, I_D = -11A$		34		S
			1955	2470	pF
	V _{DS} = -15V, V _{GS} = 0V,				pF
	f = 1MHz				pr
Irn-On Delay Time	V _{DD} = -15V, I _D = -11A		3.0	10	ns ns
	$-V_{GS} = -10V, R_{GS} = 6\Omega$				ns
	-				ns
	V _{DS} = -15V, V _{GS} = -10V, I _D = -11A		44	62	nC
	0		25	35	nC
tal Gate Charge				55	
tal Gate Charge ate to Source Gate Charge	V _{DS} = -15V, V _{GS} = -5V,		7.2	- 55	nC
atal Gate Charge ate to Source Gate Charge ate to Drain Charge	− V _{DS} = -15V, V _{GS} = -5V, I _D = -11A		-		-
ate to Source Gate Charge ate to Drain Charge			7.2		nC
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics	I _D = -11A		7.2 11.4		nC nC
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics purce to Drain Diode Forward Voltage	$I_D = -11A$ $V_{GS} = 0V, I_S = -2.1A$		7.2	-1.2	nC nC V
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics	I _D = -11A		7.2 11.4		nC nC
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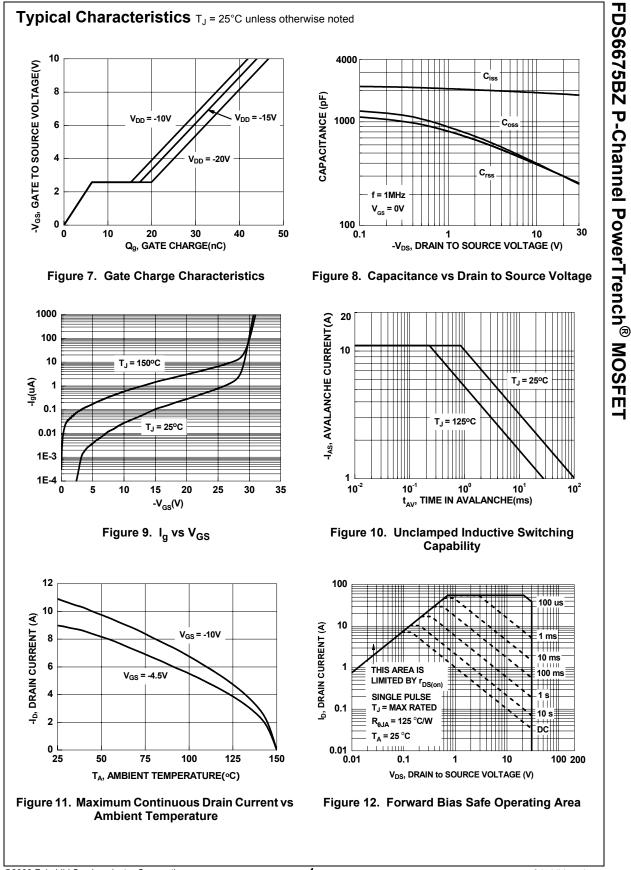
FDS6675BZ P-Channel PowerTrench[®] MOSFET

Scale 1 : 1 on letter size paper

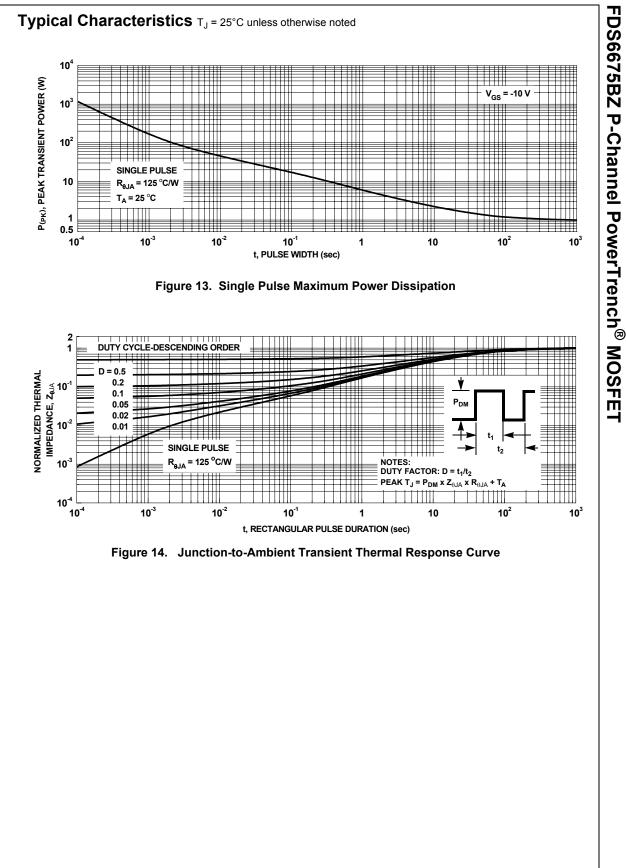
Pulse Test:Pulse Width <300 us, Duty Cycle < 2.0%
 The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



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DS6675BZ

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